

IN THE CLAIMS

Please amend the claims as follows.

1. (Withdrawn) A method for alternately contacting two wafer-like component composite arrangements, comprising:

bringing the two component composite arrangements, each provided with contact metallizations on their opposing contact surfaces, into a coverage position with their contact metallizations to form contact pairs, in which a position the contact metallizations that are to be joined together are pressed against one another;

exposing a rear of one of the two wafer-like component composite arrangements to a laser radiation, whereby the wavelength of the laser radiation is selected as a function of the degree of absorption of the component composite arrangement exposed to laser radiation at the rear, so that transmission of the laser radiation through the component composite arrangement exposed to the laser radiation at the rear is essentially suppressed or absorption of the laser radiation takes place essentially in the contact metallizations of one or both component composite arrangements, wherein the laser radiation performed by a composite arrangement of a plurality of diode lasers which are activated individually or in groups to emit laser radiation, wherein a number of the diode lasers to be activated is selected based on a position in relation to the one of the two-wafer-like component composite arrangements such that all the contact pairs or those combined into groups are exposed to laser radiation for the contacting.

2. (Withdrawn) The method according to Claim 1, wherein the substrate material of the component composite arrangement that is exposed to laser radiation at the rear is selected so that there is transmission of the laser radiation through the component composite arrangement

exposed to the laser radiation at the rear and there is absorption of the laser radiation in the contact metallizations of the component composite arrangement exposed to laser radiation at the rear.

3. (Withdrawn) The method according to Claim 1, wherein the substrate material of the component composite arrangement exposed to laser radiation at the rear is selected so that there is transmission of the laser radiation through the component composite arrangement exposed to laser radiation at the rear and there is absorption of the laser radiation in the contact metallizations of the component composite arrangement exposed to laser radiation at the rear and in the contact metallizations belonging to the opposing component composite arrangement, these contact metallizations having a larger surface area in comparison with the contact metallizations of the component composite arrangement exposed to laser radiation at the rear.

4. (Canceled)

5. (Withdrawn) The method according to Claim 1, wherein the diode laser composite arrangement is designed as a diode laser linear arrangement which is arranged at a distance below the component composite arrangement which is exposed to laser radiation at the rear, and the diode laser linear arrangement is moved in at least one axis and in parallel to the plane of extent of the component composite arrangement.

6. (Withdrawn) The method according to Claim 1, wherein the diode laser composite arrangement is designed as a diode laser matrix arrangement, whereby the diode lasers are

activated in their totality or only to the extent of a partial matrix according to the size of the component composite arrangement exposed to laser radiation at the rear.

7. (Withdrawn) The method according to Claim 1, wherein a reference temperature is measured in an intermediate space formed by the distance, the measurement being performed by a transmission device through which the laser radiation passes.

8. (Withdrawn) The method according to Claim 1, wherein for alignment of the contact metallizations in a coverage position to form the contact pairs, the component composite arrangement opposite the component composite arrangement exposed to laser radiation at the rear is positioned by means of a positioning device which acts biaxially and in parallel to the plane of extent.

9. (Currently Amended) A device for alternately contacting two wafer-like component composite arrangements comprising:

a receiving frame for supporting and holding a first component composite arrangement on a transparent panel arranged in the receiving frame;

a diode laser composite arrangement arranged inside the receiving frame and separated from the first component composite arrangement by the transparent panel;

a holding clamp for receiving a second component composite arrangement such that contact surfaces of the first and the second component composite arrangements provided with contact metallizations are arranged opposite one another;

a positioning device for relative positioning of the component composite arrangements such that the contact metallizations to be joined together form contact pairs; and
a pressure device for generating a contact pressure between the contact metallizations of the contact pairs;

wherein the diode laser composite arrangement is designed as a diode laser linear arrangement having a plurality of diode lasers arranged in a row ~~which, wherein the plurality of~~ diode lasers ~~are~~ arranged on a diode laser mount ~~that can be moved~~ ~~are configured to move~~ across the alignment of the row and in parallel to [[the]] a plane of extent of the component composite arrangement; and

wherein the diode lasers of the diode laser linear arrangement ~~can~~ ~~are configured to be activated individually or in groups, wherein a number of~~ ~~which~~ of the diode lasers of the diode laser linear arrangement ~~which~~ are needed to be activated for coverage of the respective transverse extent of ~~the-a circular~~ contact surface of the component composite arrangement is selected based on a distance to be traversed ~~by the plurality of diode lasers~~ in relation to the first component composite arrangement for acting upon [[a]] ~~the~~ circular contact surface of the first component composite arrangement, ~~wherein~~ with the diode laser linear arrangement ~~that can be moved~~ ~~is configured to move~~ in parallel to the plane of extent of the component composite arrangement.

10-11. (Canceled)

12. (Currently Amended) The device according to Claim [[11]] 9, wherein the diode laser composite arrangement is designed as a diode laser matrix arrangement having a plurality of diode lasers each arranged in rows and columns.

13. (Currently Amended) The device according to Claim 12, wherein the diode lasers of the diode laser matrix arrangement ~~can~~are configured to be activated individually or in groups such that with a coaxial alignment of the surface midpoints of the contact surface of the component composite arrangement and of the matrix surface for acting upon the circular contact surface, the diode lasers ~~can~~are configured to be activated according to the size of the contact surface either in a totality or only to the extent of a partial matrix required for coverage of the contact surface.

14. (Previously Presented) The device according to Claim 9, wherein a transmission device which serves to measure a reference temperature is provided in an intermediate space formed by a distance between the transparent panel and the diode laser composite arrangement.

15. (Currently Amended) The device according to Claim 9, wherein for alignment of the contact metallizations in a coverage position to form the contact pairs, the second component composite arrangement opposite the first component composite arrangement that is exposed to laser radiation at the rear is arranged in [[a]] the positioning device that ~~can~~is configured to be moved in at least two axes.

16. (Previously Presented) The device according to Claim 15, wherein the positioning device is designed to be triaxial such that in addition to a biaxial positioning of the component

composite arrangement in the plane of extent of the component composite arrangement, the positioning device serves to execute an adjusting movement across the plane of extent such that the positioning device serves to create the contact pressure.

17-23. (Cancelled)